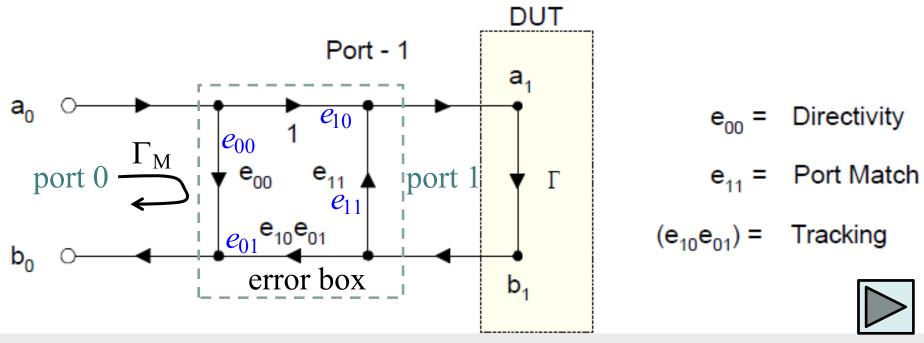
## **VNA Calibration for 1-port Measurements (3-term Error Model)**

- the 3-term error model is known as the OSM (Open-Short-Matched) cal technique (aka OSL or SOL, Open-Short-Load)
- the *cal* procedure includes 3 measurements performed before the DUT is measured: 1) open circuit, 2) short circuit, 3) matched load
- used when  $\Gamma = S_{11}$  of a single-port device is measured
- actual measurements include losses and phase delays in connectors and cables, leakage and parasitics inside the instrument these are viewed as a 2-port *error box*
- calibration aims at de-embedding these errors from the total measured *S*-parameters

# 3-term Error Model: Signal-flow Graph

[Rytting, Network Analyzer Error Models and Calibration Methods]



Note: SFG branches without a coefficient have a default coefficient of 1.

• the S-matrix of the error box contains in effect 3 unknowns

$$\mathbf{S}_{E} = \begin{bmatrix} e_{00} & 1 \\ e_{10}e_{01} & e_{11} \end{bmatrix} \quad \stackrel{\text{equivalent}}{\Leftrightarrow} \quad \mathbf{S}_{E}' = \begin{bmatrix} e_{00} & e_{01} \\ e_{10} & e_{11} \end{bmatrix}$$

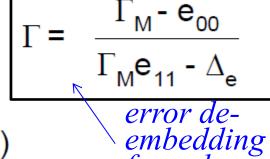
# **3-term Error Model: Error-term Equations**

# **Measured**

## <u>Actual</u>

$$\Gamma_{\rm M} = \frac{b_0}{a_0} = \frac{e_{00} - \Delta_{\rm e} \Gamma}{1 - e_{11} \Gamma}$$





$$\Delta_{e} = e_{00}e_{11} - (e_{10}e_{01})$$

Using the result from the example on sl. 10 and the signal flow graph in sl. 12, prove the formula

$$\Gamma_{\rm M} = \frac{e_{00} - \Delta_e \cdot \Gamma}{1 - e_{11} \Gamma}$$

Prove that the S-matrices of the error box in sl. 12,  $S_E$  and  $S'_E$ , result in the same expression for  $\Gamma_M$ .

#### 3-term Error Model

• the 3 calibration measurements with the 3 standard known loads ( $\Gamma_1$ ,  $\Gamma_2$ ,  $\Gamma_3$ ) produce 3 equations for the 3 unknown error terms

$$\begin{aligned} & \mathbf{e}_{00} + \Gamma_{1}\Gamma_{\text{M1}}\mathbf{e}_{11} - \Gamma_{1}\Delta_{\text{e}} = \Gamma_{\text{M1}} \\ & \mathbf{e}_{00} + \Gamma_{2}\Gamma_{\text{M2}}\mathbf{e}_{11} - \Gamma_{2}\Delta_{\text{e}} = \Gamma_{\text{M2}} \\ & \mathbf{e}_{00} + \Gamma_{3}\Gamma_{\text{M3}}\mathbf{e}_{11} - \Gamma_{3}\Delta_{\text{e}} = \Gamma_{\text{M3}} \end{aligned}$$

$$\begin{vmatrix} \mathbf{e}_{00} + \Gamma_{1}\Gamma_{\mathrm{M1}}\mathbf{e}_{11} - \Gamma_{1}\Delta_{\mathrm{e}} = \Gamma_{\mathrm{M1}} \\ \mathbf{e}_{00} + \Gamma_{2}\Gamma_{\mathrm{M2}}\mathbf{e}_{11} - \Gamma_{2}\Delta_{\mathrm{e}} = \Gamma_{\mathrm{M2}} \end{vmatrix} = \begin{vmatrix} \operatorname{linear\ system\ for\ } \mathbf{x}^{T} = [e_{00}, e_{11}, \Delta_{e}] \\ \mathbf{e}_{00} + \Gamma_{2}\Gamma_{\mathrm{M2}}\mathbf{e}_{11} - \Gamma_{2}\Delta_{\mathrm{e}} = \Gamma_{\mathrm{M2}} \end{vmatrix} \Rightarrow \langle (e_{00}, e_{11}, \Delta_{e}) \rangle \Rightarrow \begin{bmatrix} \Gamma = \frac{\Gamma_{\mathrm{M}} - e_{00}}{\Gamma_{\mathrm{M}}e_{11} - \Delta_{e}} \\ \Gamma = \frac{\Gamma_{\mathrm{M}} - e_{00}}{\Gamma_{\mathrm{M}}e_{11} - \Delta_{e}} \end{bmatrix}$$

$$= e_{00} + \Gamma_{3}\Gamma_{\mathrm{M3}}\mathbf{e}_{11} - \Gamma_{3}\Delta_{\mathrm{e}} = \Gamma_{\mathrm{M3}} \Rightarrow e_{\mathrm{M3}} \Rightarrow e_{$$

• ideally, in the OSM calibration,

$$\Gamma_1 = \Gamma_0 = 1$$

$$\Gamma_2 = \Gamma_s = -1$$

$$\Gamma_3 = \Gamma_m = 0$$

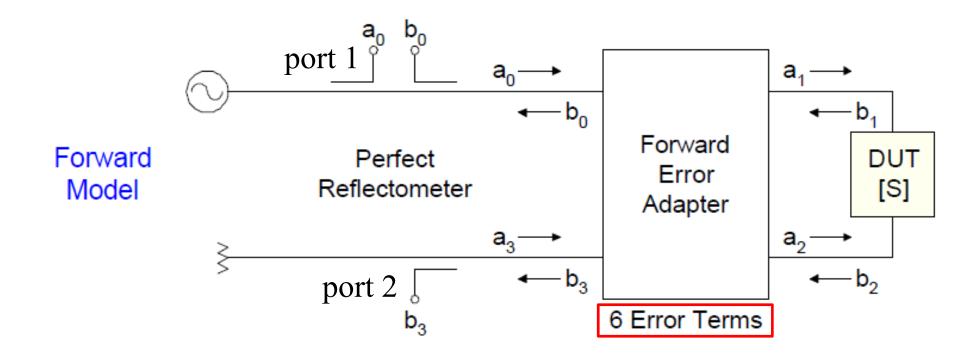
• for accurate results, one has to know the exact values of  $\Gamma_{\rm o}$ ,  $\Gamma_{\rm s}$  and  $\Gamma_{\rm m}$  – use manufacturer's cal kits!

## 2-port Calibration: Classical 12-term Error Model

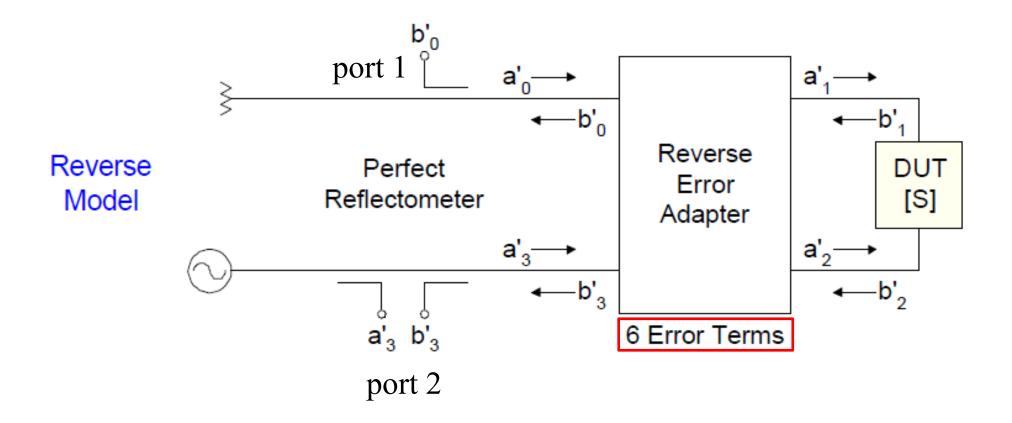
[Rytting, Network Analyzer Error Models and Calibration Methods]

consists of two models:

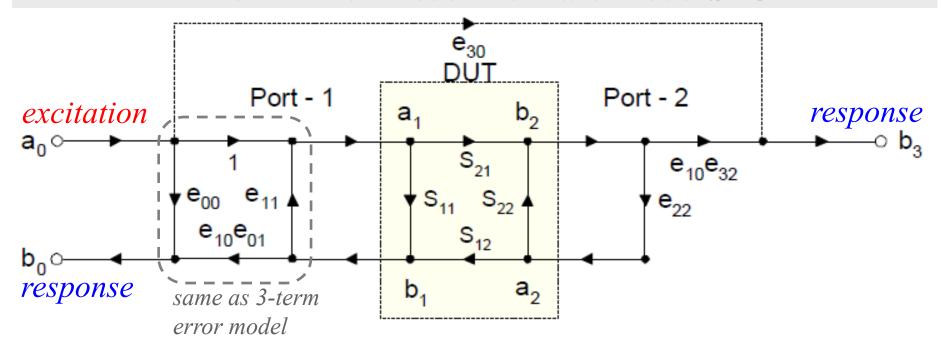
- forward (excitation at port 1): models errors in  $S_{11M}$  and  $S_{21M}$
- reverse (excitation at port 2): models errors in  $S_{22M}$  and  $S_{12M}$



#### 12-term Error Model: Reverse Model



#### 12-term Error Model: Forward-model SFG



$$e_{00}$$
 = Directivity

$$(e_{10}e_{01})$$
 = Reflection Tracking

$$(e_{10}e_{32})$$
 = Transmission Tracking

$$e_{22}$$
 = Port-2 Match

$$e_{30}$$
 = Leakage

$$S_{11M} = \frac{b_0}{a_0} = e_{00} + (e_{10}e_{01}) \frac{S_{11} - e_{22}\Delta_S}{1 - e_{11}S_{11} - e_{22}S_{22} + e_{11}e_{22}\Delta_S}$$

$$S_{21M} = \frac{b_3}{a_0} = e_{30} + (e_{10}e_{32}) \frac{S_{21}}{1 - e_{11}S_{11} - e_{22}S_{22} + e_{11}e_{22}\Delta_S}$$

$$(*) \qquad \Delta_S = S_{11}S_{22} - S_{21}S_{12}$$

#### 12-term Error Model: Forward-model SFG

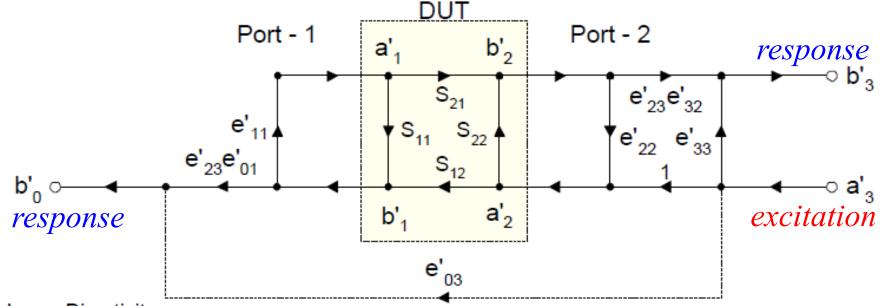
Using signal-flow graph transformations derive the formulas for  $S_{11M}$  and  $S_{21M}$  in the previous slide.

$$S_{11M} = \frac{b_0}{a_0} = e_{00} + (e_{10}e_{01}) \frac{S_{11} - e_{22}\Delta_S}{1 - e_{11}S_{11} - e_{22}S_{22} + e_{11}e_{22}\Delta_S}$$

$$S_{21M} = \frac{b_3}{a_0} = e_{30} + (e_{10}e_{32}) \frac{S_{21}}{1 - e_{11}S_{11} - e_{22}S_{22} + e_{11}e_{22}\Delta_S}$$

$$(*) \qquad \Delta_S = S_{11}S_{22} - S_{21}S_{12}$$

#### 12-term Error Model: Reverse-model SFG



e'<sub>33</sub> = Directivity

$$(e'_{23}e'_{32}) = Reflection Tracking$$

$$S_{22M} = \frac{b'_{3}}{a'_{3}} = e'_{33} + (e'_{23}e'_{32}) \frac{S_{22} - e'_{11} \Delta_{S}}{1 - e'_{11}S_{11} - e'_{22}S_{22} + e'_{11}e'_{22} \Delta_{S}}$$

$$S_{12M} = \frac{b'_{0}}{a'_{3}} = e'_{03} + (e'_{23}e'_{01}) \frac{S_{12}}{1 - e'_{11}S_{11} - e'_{22}S_{22} + e'_{11}e'_{22} \Delta_{S}}$$

$$(**) \qquad \Delta_{S} = S_{11}S_{22} - S_{21}S_{12}$$

#### 12-term Calibration Method

- **Step 1:** (*Port 1 Calibration*) using the OSM 1-port procedure, obtain  $e_{11}$ ,  $e_{00}$ , and  $\Delta_e$ , from which  $(e_{10}e_{01})$  is obtained.
- (sl. 12)
- **Step 2:** (*Isolation*) Connect matched loads  $(Z_0)$  to both ports.  $(S_{21} = 0)$  The measured  $S_{21M}$  yields  $e_{30}$  directly.  $(S_{12M} = e'_{03})$
- **Step 3:** (*Thru*) Connect ports 1 and 2 directly.  $(S_{21} = S_{12} = 1, S_{11} = S_{22} = 0)$

Obtain 
$$e_{22}$$
 and  $e_{10}$   $e_{32}$  from eqns. (\*) using 
$$S_{21} = S_{12} = 1, S_{11} = S_{22} = 0.$$

$$transmission tracking \rightarrow e_{10}e_{32} = (S_{21M} - e_{30})(1 - e_{11}e_{22})$$

- All 6 error terms of the forward model are now known.
- Same procedure is repeated for port 2.

## 12-term Calibration Method: Error De-embedding

$$\begin{split} S_{11} &= \frac{\left(\frac{S_{11M} - e_{00}}{e_{10}e_{01}}\right) \left[1 + \left(\frac{S_{22M} - e'_{33}}{e'_{23}\,e'_{32}}\right) e'_{22}\right] - e_{22} \left(\frac{S_{21M} - e_{30}}{e_{10}e_{32}}\right) \left(\frac{S_{12M} - e'_{03}}{e'_{23}\,e'_{01}}\right)}{D} \\ S_{21} &= \frac{\left(\frac{S_{21M} - e_{30}}{e_{10}e_{32}}\right) \left[1 + \left(\frac{S_{22M} - e'_{33}}{e'_{23}\,e'_{32}}\right) (e'_{22} - e_{22})\right]}{D} \\ S_{22} &= \frac{\left(\frac{S_{22M} - e'_{33}}{e'_{23}\,e'_{32}}\right) \left[1 + \left(\frac{S_{11M} - e_{00}}{e_{10}e_{01}}\right) e_{11}\right] - e'_{11} \left(\frac{S_{21M} - e_{30}}{e_{10}e_{32}}\right) \left(\frac{S_{12M} - e'_{03}}{e'_{23}\,e'_{01}}\right)}{D} \\ S_{12} &= \frac{\left(\frac{S_{12M} - e'_{03}}{e'_{23}\,e'_{01}}\right) \left[1 + \left(\frac{S_{11M} - e_{00}}{e_{10}e_{01}}\right) (e_{11} - e'_{11})\right]}{D} \end{split}$$

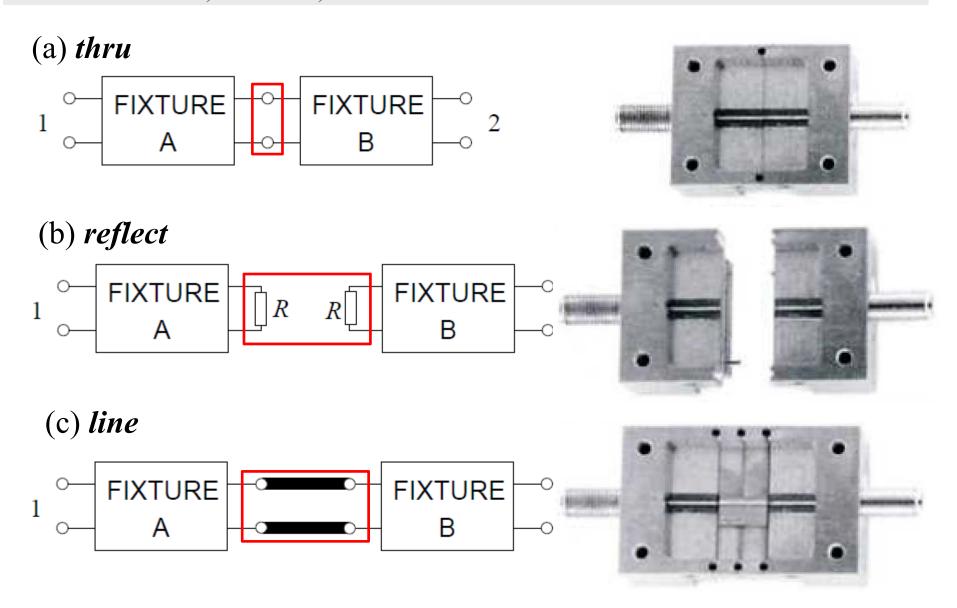
$$D = \left\lceil 1 + \left( \frac{S_{11M} - e_{00}}{e_{10} e_{01}} \right) e_{11} \right\rceil 1 + \left( \frac{S_{22M} - e'_{33}}{e'_{23} e'_{32}} \right) e'_{22} \right\rceil - \left( \frac{S_{21M} - e_{30}}{e_{10} e_{32}} \right) \left( \frac{S_{12M} - e'_{03}}{e'_{23} e'_{01}} \right) e_{22} e'_{11} e'_{22} e'_{23} e'_{2$$

## 2-port Thru-Reflect-Line Calibration

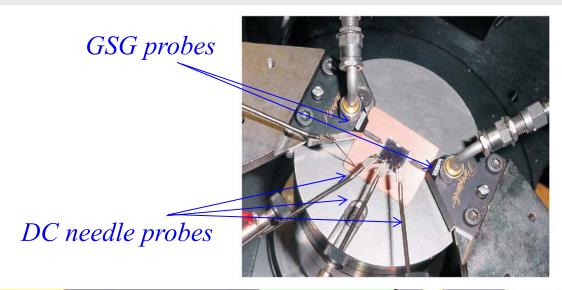
- TRL (Thru-Reflect-Line) calibration is used when classical standards such as open, short and matched load cannot be realized
- TRL is the calibration used when measuring devices with non-coaxial terminations (HMIC and MMIC)
- TRL calibration is based on an 8-term error model
- TRL calibration requires three (2-port) custom calibration structures

thru: the 2 ports must be connected directly, sets the reference planes reflect: same load on each port (preferred); must have large reflection line (or delay): 2 ports connected with system interconnect (represents the IC interconnect for the measured DUT and sets  $Z_0$ )

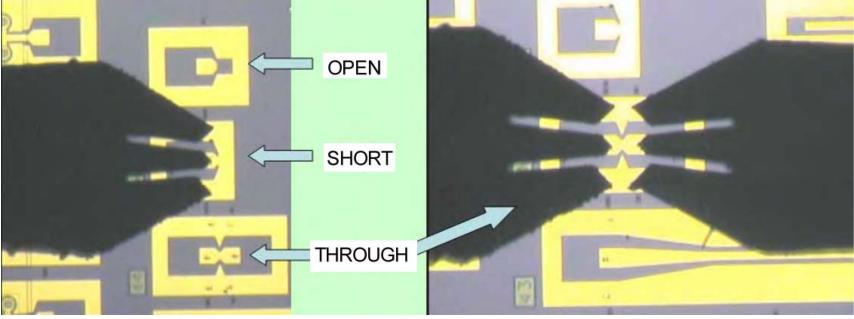
# Thru, Reflect, and Line Calibration Connections



# **Thru-Reflect-Line Calibration Fixtures**



[Steer, Microwave and RF Design]

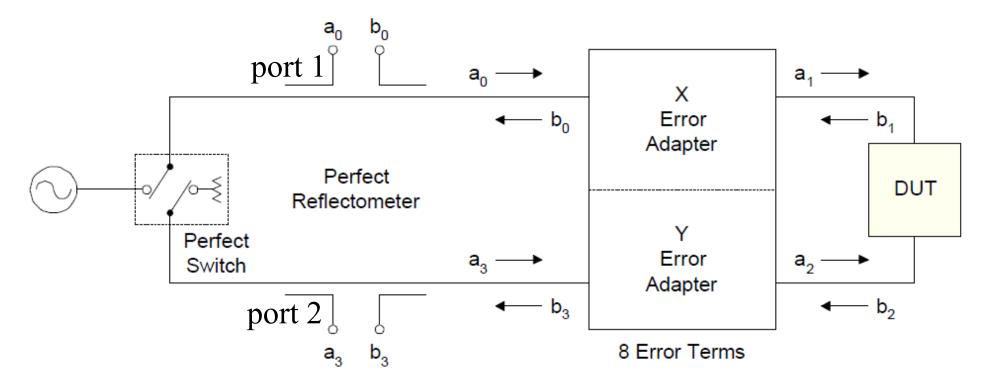


ElecEng4FJ4

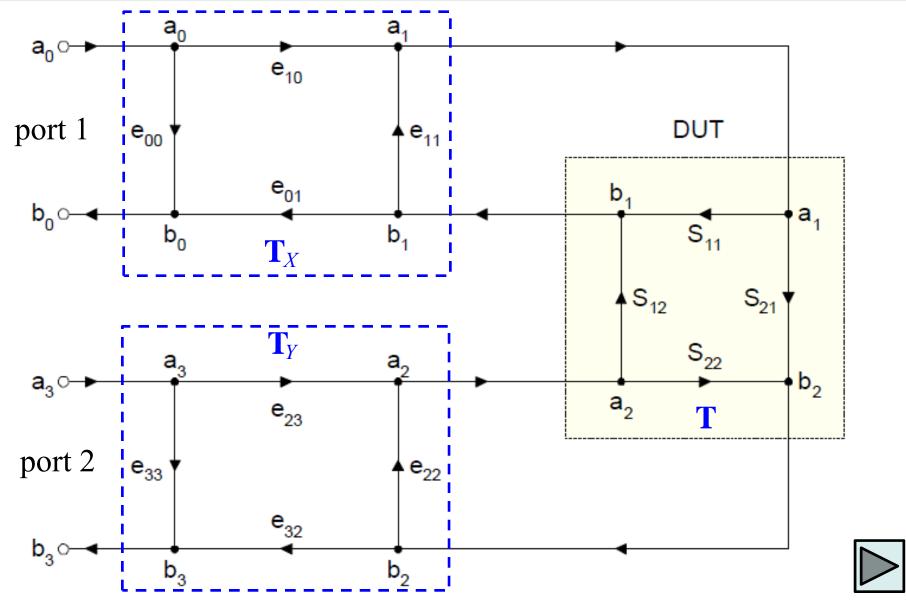
LECTURE 13: VECTOR NETWORK ANALYZERS AND SIGNAL FLOW GRAPHS

# 2-port Calibration: 8-term Error Model

### [Rytting, Network Analyzer Error Models and Calibration Methods]



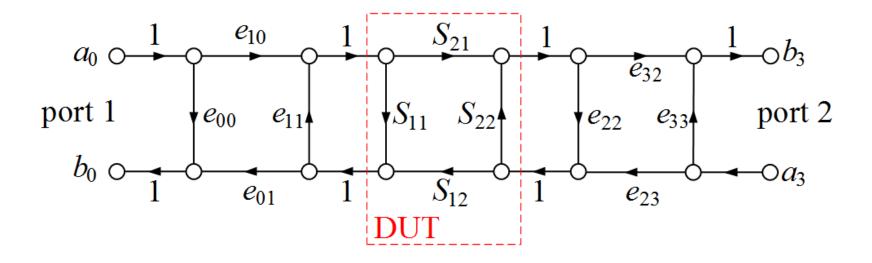
# Signal-flow Graph of 8-term Error Model



LECTURE 13: VECTOR NETWORK ANALYZERS AND SIGNAL FLOW GRAPHS

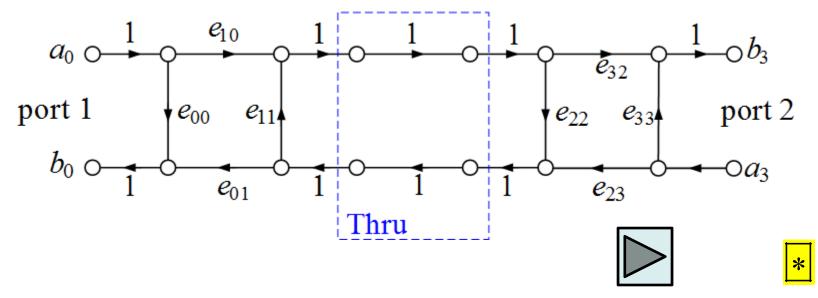
#### TRL Calibration: SFG with DUT

• unfolded SFG of the DUT measurement



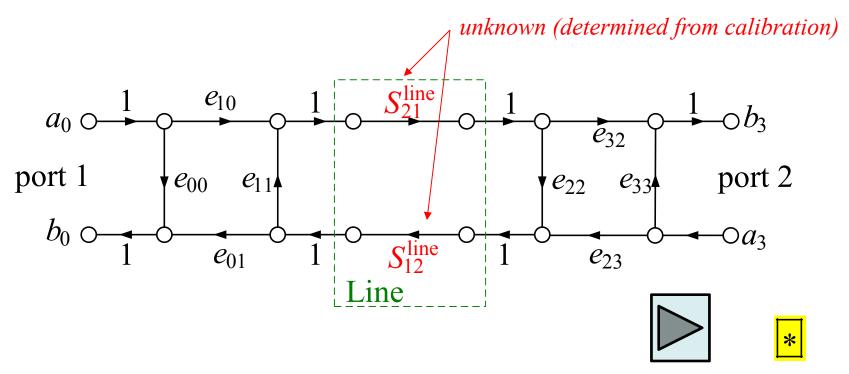
#### TRL Calibration: SFG of Thru Measurement

- we must know all 4 *Thru S*-parameters
- if *Thru* is assumed of zero length, then reference plane for all ports is set in its middle:  $S_{21}^{thru} = S_{12}^{thru} = 1$
- if *Thru* assumed perfectly matched, then  $S_{11}^{thru} = S_{22}^{thru} = 0$  (then it must be made with the same line as that in the *Line* standard, which determines  $Z_0$ )



#### TRL Calibration: SFG of *Line* Measurements

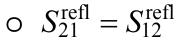
- we need to know only 2 *Line S*-parameters
- *Line* determines  $Z_0$  and is, therefore, assumed perfectly matched to  $Z_0$ :  $S_{11}^{\text{line}} = S_{22}^{\text{line}} = 0$  (2 known parameters)
- must have different physical length compared to *Thru*

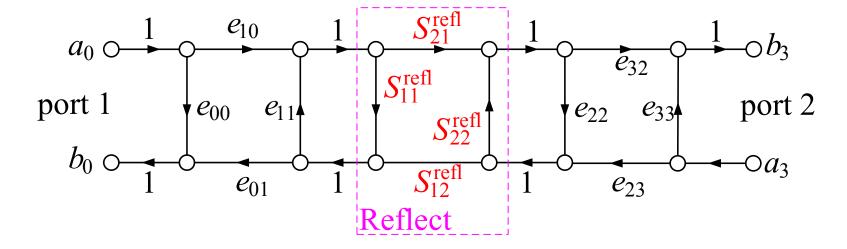


# TRL Calibration: SFG of Reflect Measurements

- must have high reflection  $(S_{11}^{\text{refl}}, S_{22}^{\text{refl}})$  on both ports!
- only one piece of information is needed, for example

o 
$$S_{11}^{\text{refl}} = S_{22}^{\text{refl}}$$
 (most common)







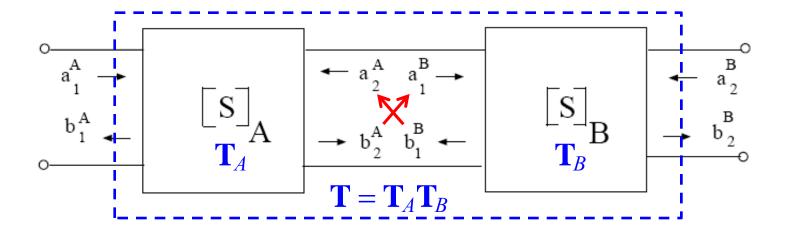
## **Scattering Transfer (or Cascade) Parameters**

• when a network is a cascade of 2-port networks, often the scattering transfer (*T*-parameters) are used

$$\begin{bmatrix} V_1^- \\ V_1^+ \end{bmatrix} = \begin{bmatrix} T_{11} & T_{12} \\ T_{21} & T_{22} \end{bmatrix} \begin{bmatrix} V_2^+ \\ V_2^- \end{bmatrix} \quad \text{or} \quad \begin{bmatrix} b_1 \\ a_1 \end{bmatrix} = \begin{bmatrix} T_{11} & T_{12} \\ T_{21} & T_{22} \end{bmatrix} \begin{bmatrix} a_2 \\ b_2 \end{bmatrix}$$

• relation to S-parameters

$$\begin{bmatrix} T_{11} & T_{12} \\ T_{21} & T_{22} \end{bmatrix} = S_{21}^{-1} \begin{bmatrix} -\Delta_S & S_{11} \\ -S_{22} & 1 \end{bmatrix}, \ \Delta_S = S_{11}S_{22} - S_{12}S_{21}$$



## 8-term Error Model in Terms of T-parameters for TRL Calibration

#### <u>MEASURED</u>

$$T_M = T_X T T_Y$$



$$T = T_X^{-1} T_M T_Y^{-1}$$
error do emboddino

$$\mathbf{T} = \frac{1}{S_{21}} \begin{bmatrix} -\Delta_S & S_{11} \\ -S_{22} & 1 \end{bmatrix}$$

$$\Delta_{S} = S_{11}S_{22} - S_{12}S_{21}$$

$$\mathbf{T} = \frac{1}{S_{21}} \begin{bmatrix} -\Delta_{S} & S_{11} \\ -S_{22} & 1 \end{bmatrix}$$

$$\Delta_{S} = S_{11}S_{22} - S_{12}S_{21}$$

$$\mathbf{T} \text{ in terms of } \mathbf{S}$$

$$\Delta_{M} = S_{11M}S_{22M} - S_{12M}S_{21M}$$

$$\Delta_{\rm M} = {\sf S}_{11M} {\sf S}_{22M} - {\sf S}_{12M} {\sf S}_{21M}$$

$$T_{X} = \frac{1}{e_{10}} \begin{bmatrix} -\Delta_{X} & e_{00} \\ -e_{11} & 1 \end{bmatrix}$$

$$\Delta_X = e_{00}e_{11} - e_{10}e_{01}$$

$$T_{X} = \frac{1}{e_{10}} \begin{bmatrix} -\Delta_{X} & e_{00} \\ -e_{11} & 1 \end{bmatrix}$$

$$T_{X} = \frac{1}{e_{10}} \begin{bmatrix} -\Delta_{Y} & e_{22} \\ -e_{33} & 1 \end{bmatrix}$$

$$\Delta_{X} = e_{00}e_{11} - e_{10}e_{01}$$

$$T_{X} = \frac{1}{e_{32}} \begin{bmatrix} -\Delta_{Y} & e_{22} \\ -e_{33} & 1 \end{bmatrix}$$

$$\Delta_{Y} = e_{22}e_{33} - e_{32}e_{23}$$

$$\Delta_{Y} = e_{22}e_{33} - e_{32}e_{23}$$

#### 8-term Error Model for TRL Calibration

• the number of unknown error terms is actually 7 in the simple cascaded TRL network (see sl. 26)

$$\mathbf{T}_{\mathbf{M}} = \underbrace{\frac{1}{(\mathbf{e}_{10}\mathbf{e}_{32})} \begin{bmatrix} -\Delta_{\mathbf{X}} & \mathbf{e}_{00} \\ -\mathbf{e}_{11} & 1 \end{bmatrix}}_{\mathbf{A}} \mathbf{T} \underbrace{\begin{bmatrix} -\Delta_{\mathbf{Y}} & \mathbf{e}_{22} \\ -\mathbf{e}_{33} & 1 \end{bmatrix}}_{\mathbf{B}} = \underbrace{\frac{1}{(\mathbf{e}_{10}\mathbf{e}_{32})} \mathbf{A} \mathbf{T} \mathbf{B}}_{\mathbf{B}}$$

$$\Rightarrow \mathbf{T} = (e_{10}e_{32}) \mathbf{A}^{-1} \mathbf{T}_{\mathbf{M}} \mathbf{B}^{-1}$$

- TRL measurement procedure
  - (1)  $T_{M1} = T_X T_{C1} T_Y \rightarrow$  measured with 2-port cal standard #1
  - (2)  $T_{M2} = T_X T_{C2} T_Y \rightarrow \text{measured with 2-port cal standard } \#2$
  - (3)  $T_{M3} = T_X T_{C3} T_Y \rightarrow \text{measured with 2-port cal standard } \#3$
  - (4)  $T_M = T_X T T_Y \rightarrow \text{measured with DUT}$
- we need to find the 7 error terms from (1), (2) and (3)

#### 8-term Error Model for TRL Calibration

• measuring the 3 two-port cal standards yields 12 independent equations while we have only 7 error terms

$$THRU(4) + LINE(4) + REFLECT(4)$$

- thus 5 parameters of the 3 cal standards need not be known and can be determined from the calibration measurements
- which 5 parameters are chosen for which cal standards is important in order to reduce errors and avoid singular matrices
  - cal standard #1 (thru) T<sub>C1</sub> must be completely known (common choice: ref. plane in the middle, perfect match)
  - cal standard #2 (line)  $T_{C2}$  can have 2 unknowns (sl. 29)
  - cal standard #3 (reflect) T<sub>C3</sub> can have 3 unknowns

## **VNA Calibration – Summary**

- errors are introduced when measuring a device due to parasitic coupling, leakage, reflections and imperfect directivity
- these errors must be de-embedded from the overall measured *S*-parameters
- the de-embedding relies on the measurement of known or partially known cal standards calibration measurements, which precede the measurement of the DUT
- 1-port calibration uses the 3-term error model and the OSM method
- 2-port calibration may use 12-term or 8-term error models
- the 12-term error model requires *OSM* at each port, *isolation*, and *thru* measurements
- the 8-term error model with the TRL technique is widely used for non-coaxial devices requires custom fixtures for *thru*, *reflect* & *line*
- there exists also a 16-term error model, many other cal techniques